

Notice of References Cited	Application/Control No. 10/521,176	Applicant(s)/Patent Under Reexamination OKAMURA ET AL.	
	Examiner NARAYAN K. BHAT	Art Unit 1634	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,929,194	07-1999	Woo et al.	528/229
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 03/020425	03-2003	USA	Mao et al	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Langer et al, Thermal conductivity of thin metallic films measured by photothermal profile analysis, 1997, Rev. Sci. Instrum. 68, 1510-1513.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.